

**Search Notes**

Application/Control No.

10/069,596

Examiner

Hien Tran

Applicant(s)/Patent under  
Reexamination

NAKAJIMA ET AL.

Art Unit

1764

**SEARCHED**

Class	Subclass	Date	Examiner
422	177, 180, 171	5/19/2005	HT
updated	search	11/4/2005	HT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Image class/subclass search / Inventors' names search / Text search	5/19/2005	HT